

Application No.	Applicant(s)	
10/767,273	LEE ET AL.	
Examiner	Art Unit	
James K. Truiillo	2116	

SEARCHED					
Class	Subclass	Date	Examiner		
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713	400, 401 500,600	8/25/04	IKT		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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365	233	8/25/04			
327	284	+	1		
711	167	1	1		

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	DATE	EXMR	
DATABASES SEARCHED: EAST NPL: IEEE, ACM	8/22/04 V 8/25/04	AKT	
NPLI ILEE, ACM	8/25/04		
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